

5    ABSTRACT

Index head in a semiconductor device test handler for mounting semiconductor device in a test socket at a test site, wherein a force pressing down a semiconductor device is accurately controlled by means of a force transducer fitted to a head holder, a precise temperature control of the semiconductor device is made by direct heat transfer to a picked up semiconductor device from an electric heater fitted to the head, and a smooth alignment is made by a compliance part even if there is an alignment error between the index head and/or the test socket, thereby permitting a faster operation of the index head.

10